## **Vertical Planar Near-field Beam Pattern Measuring System**

## **General description**

The Millimeter Wave Laboratory of Universidad de Chile has developed an automated near-field measuring system up to 50 GHz. The system's most important elements are an anechoic chamber, an inverted "T" planar beam scanner with a probe antenna, the scanner controller, a PNA Microwave network analyzer and a workstation with the control program.

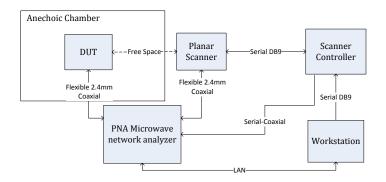


Figure 1: Block diagram of the Near-field Beam Pattern Measuring System.

NCS-M2

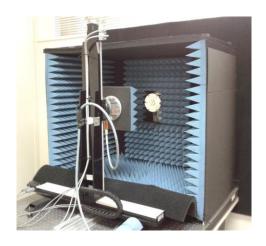


Figure 2: Planar Near-Field Beam Pattern measuring System.

PNA Microwave network analyzer

## **Specifications**

Model N°

**Anechoic Chamber** 

micenoic chamber		1 Mi Miciowave network	andiy Zei
Absorber Manufacturer	Eccosorb	Manufacturer	Agilent
Model N°	VHP-NRL	Model N°	E8364C
Reflectibity@45GHz	~-40dB	Frequency Range	10MHz to 50 GHz
		Power Range	
Planar Scanner		@10 to 20 GHz	-24 to +3 dBm
Manufacturer	Newmark Systems	@20 to 30 GHz	-23 to 0 dBm
Model N°	STG-24-C	@30 to 40 GHz	-23 to -4 dBm
Resolution	1 $\mu$ m	@40 to 45 GHz	-25 to -5 dBm
Planarity	<0.15 mm	@45 to 50 GHz	-25 to -10 dBm
Scan Speed (Max)	1 in/s	Noise Floor	
Scan Area	60 cm X 60 cm	10 Hz IF bandwidth	
Probe Carriage Capacity	6.8 Kg	@10 to 20 GHz	<-120 dBm
D 1 4 .		@20 to 40 GHz	<-114 dBm
Probe Antenna		@40 to 50 GHz	<-114 dBm
Manufacturer	MI Technologies	1 KHz IF bandwidth	
Model	MI-6970-WR22	@10 to 20 GHz	<-100 dBm
Scanner Controller		@20 to 40 GHz	<-94 dBm
		@40 to 50 GHz	<-94 dBm
Manufacturer	Newmark Systems	-	

## **ALMA Band 1 Test Setup Specifications**

Test Frequencies	35, 42.5 and 50 GHz	Typical Test Power	
DUT to Probe Distance (D)	179 mm	@35GHz	-5dBm
DUT Aperture Diameter(A)	31.68 mm	@42.5GHz	-5dBm
Sampling Distance (S)	$0.48 \lambda$	@50GHz	-10dBm
Maximum Far-Field Angle ( $lpha$ )	40°		
Total N° of Points (N)		$/[2 \cdot D \cdot \tan(\alpha)]$	$+A$ ] $\begin{pmatrix} 2 \\ 1 \end{pmatrix}^2$
@35GHz	6724	$N = \left( \left[ \frac{2 \cdot D \cdot \tan(\alpha)}{S \cdot \lambda} \right] \right)$	— +1)
@42.5GHz	10000	(1	1 /
@50GHz	13689	$L = S \cdot \lambda \cdot (\sqrt{N} - 1)$	
Scan Linear Length (L)			
@35GHz	0.333027 m		
@42.5GHz	0.335203 m		
@50GHz	0.333849 m		

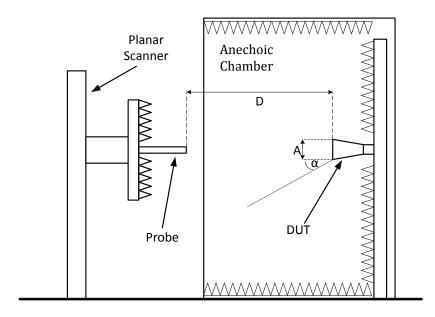


Figure 3: Diagram indicating the variables needed for ALMA Band 1 test setup.